

# RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1267	Apr-96	9612 A1	HYUNDAI	DL603183AAL	1.2μ OX/NI	16 SOIC

**STRESS/JOB NO.**

**READPOINT**

**(Sample Size/No. of Fails)**

Preconditioning (P/C):  
HTC Vapor Phase  
P-17251

<u>Electrical</u>	<u>Cum %</u>
232/0	0.0%

Sonoscan  
P-17298

<u>Post Vapor Phase</u>
2/0

Infant / High Voltage Life  
125°C, -4.0 & +6.0 V  
P-17299, P-17411

<u>48 Hr</u>	<u>336 Hr</u>	<u>1K Hr</u>	<u>*Failure Rate</u>
230/0	77/0	77/0	82 Fits

\*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle  
-55°C to +125°C  
P-17412

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
38/0	38/0	0.0%

Biased Moisture  
85°C/85% RH, 5.5 V.  
P-17413

<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
77/0	77/0	0.0%

Autoclave  
121°C/100% RH, 2 Atmos  
P-17414

<u>168 Hr</u>	<u>Cum %</u>
38/1	2.6%
F1	

**Failure Mode**

F1: Lkg

**Failure Analysis**

In process, 960111